

BOUNDARY SCAN WITH STROBED PAD DRIVER ENABLE

ABSTRACT

A circuit and a method are provided for testing the enable function of Boundary Scan Register bits that control the driver of unconnected I/O pins of an 1149.1-compliant IC during the IC's reduced pin-count access manufacturing test, and to test the connections to these pins during the test of a circuit board containing the IC, without causing excessive current if a pin is inadvertently short circuited.